

Rules and Charges of SPM Facility Usage

1. Multimode Scanning Probe Microscope, AFM/STM (NT-MDT)

AFM Imaging: Contact / Semi-contact mode

Special Techniques available:

In Air and Vacuum: Scanning Tunneling Microscopy (STM), Lateral Force Microscopy (LFM), Phase Imaging, Force Modulation, Magnetic Force Microscopy (MFM), Adhesion force imaging, AFM Lithography, Spreading Resistance Imaging (SRI), Scanning Kelvin Probe Microscopy (SKM), Heating Stage Operations, Nanosclerometry with AFM-Nanoindentation.

In Liquid: Contact AFM/LFM/Adhesion Force Imaging/Force Modulation, Resonant Mode, Phase Imaging, AFM Lithography, Electrochemical AFM/STM Imaging

Faculty in charge: Dr. P.Biji, Assistant Professor in Nanotechnology, PSGIAS

Email: pbm@psgias.ac.in

Researchers from various institutions are welcome to use these facilities. Those who want to avail these facilities are requested to send the filled job requisition form (Downloadable from PSGIAS website) and advance DD/Cheque (if applicable) in favour of “**PSG Centre for Sponsored Research & Consultancy**” payable at Coimbatore to:

Dr. P. Biji, Associate Professor,

I-106, SPM/Raman Facility

PSG Institute of Advanced Studies PB No: 1609, Peelamedu Coimbatore-641 004

E-mail: pbm@psgias.ac.in

Rules and Charges for using the facility

1. To avail any facility prior registration is a must.
2. Analysis will be done on charge basis.
3. Appointment will be given as per queue and the allotted time for the slot will be informed through E-mail.

4. For a better analysis, basic details about the sample should be given.
5. Refunds will not be made in any case.
6. Sample preparation should be done by the user.
7. External colleges & Universities and industry users should pay the charges in advance along with the samples for characterization

8. Analysis Charges:

Multimode SPM (NTMDT)-Imaging and Special techniques-analysis charges

Modes	Internal (PSG Institutions (INR)	External Colleges & Universities (INR)	Industry (INR)
Atomic Force Microscopy (AFM)	500	1500	3000
Lateral Force Microscopy (LFM)	500	1500	3000
Spreading Resistance Imaging (SRI)	500	1600	3200
Force Modulation mode	500	1500	3000
Phase imaging	500	1500	3000
Adhesion Force Imaging	400	1200	2400
Magnetic Force Microscopy (MFM)	600	2000	4000
Kelvin Probe Microscopy	600	2000	4000
Heating Stage operations	600	2000	4000
Nanoindentation	600	2000	4000
Liquid stage Operations	600	2000	4000
In Vacuum condition	600	2000	4000
Scanning Tunneling Microscopy	600	2000	4000
Electrochemical AFM/STM	1000	2000	4000
Lithography	600	2000	4000

Note: 18% GST to be added to these basic charges